

DK-103837-UL

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

CB TEST CERTIFICATE

Product
Name and address of the applicant
Name and address of the manufacturer

Name and address of the factory

Note: When more than one factory, please report on page 2

Ratings and principal characteristics

Trademark / Brand (if any)

Component IC Current Limiter

FAIRCHILD SEMICONDUCTOR TECHNOLOGY (SHANGHAI) CO LTD

UNIT 01-07, 7F, LONGEMONT YES TOWER NO.399 KAIXUAN RD, CHANGNING DISTRICT SHANGHAI 200050 CHINA

FAIRCHILD SEMICONDUCTOR TECHNOLOGY (SHANGHAI) CO LTD UNIT 01-07, 7F, LONGEMONT YES TOWER NO.399 KAIXUAN RD, CHANGNING DISTRICT SHANGHAI 200050 CHINA

ON SEMICONDUCTOR SENAWANG INDUSTRIAL ESTATE, LOT 122 70450 SEREMBAN MALAYSIA

Additional Information on page 2

See Page 2

ON



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

Additional information (if necessary may also be reported on page 2)

A sample of the product was tested and found to be in conformity with

As shown in the Test Report Ref. No. which forms part of this Certificate

NCP382HD05, NCP382HD10, NCP382HD15, NCP382LD05, NCP382LD10, NCP382LD15 See Page 2

Additionally evaluated to EN 62368-1:2014/A11:2017; National Differences specified in the CB Test Report.

IEC 62368-1:2014

E467988-A6007-CB-1 issued on 2020-10-05

This CB Test Certificate is issued by the National Certification Body

UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA For full legal entity names see www.ul.com/ncbnames Signature:

Jan-Erik Storgaard

